

# PATENT ABSTRACTS OF JAPAN

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(21)Application number : **04-126971** (71)Applicant : **NEC CORP**  
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## (54) PROBE CARD

### (57)Abstract:

PURPOSE: To obtain a good contact pressure, even if there is an error in parallelism in a probe card between a chip having a narrow pad and the probe card.

CONSTITUTION: A contactor 8 implanted upright on a flexible printed circuit board 10 is caused to be pressed to an electrode pad D of a chip 6 under test with an actuator 12 for which a pressure of solution is controlled by a pre-pressure pipe 13 through an input/output hole H and the pressure is detected and controlled with a pressure sensor provided within the actuator.

